

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E6 instruction tests for VRR-h encoded:
				5 *
				6 * E677 VCP - VECTOR COMPARE DECIMAL
				7 *
				8 * James Wekel June 2024
				9 *****
				10
				11 *****
				12 *
				13 * basic instruction tests
				14 *
				15 *****
				16 * This program tests proper functioning of the z/arch E6 VRR-h vector
				17 * compare decimal. Exceptions are not tested.
				18 *
				19 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				20 * obvious coding errors. None of the tests are thorough. They are
				21 * NOT designed to test all aspects of any of the instructions.
				22 *
				23 *****
				24 *
				25 * *Testcase zvector-e6-15-comparedecimal: VECTOR E6 VRR-h instruction
				26 * *
				27 * * Zvector E6 tests for VRR-h encoded instruction:
				28 * *
				29 * * E677 VCP - VECTOR COMPARE DECIMAL
				30 * *
				31 * * # -----
				32 * * # This tests only the basic function of the instruction.
				33 * * # Exceptions are NOT tested.
				34 * * # -----
				35 * *
				36 * main size 2
				37 * numcpu 1
				38 * sysclear
				39 * archlvl z/Arch
				40 *
				41 * diag8cmd enable # (needed for messages to Hercules console)
				42 * loadcore "\$(testpath)/zvector-e6-15-comparedecimal.core" 0x0
				43 * diag8cmd disable # (reset back to default)
				44 *
				45 * *Done
				46 *
				47 *****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				49 *****
				50 * FCHECK Macro - Is a Facility Bit set?
				51 *
				52 * If the facility bit is NOT set, an message is issued and
				53 * the test is skipped.
				54 *
				55 * Fcheck uses R0, R1 and R2
				56 *
				57 * eg. FCHECK 134, 'vector-packed-decimal'
				58 *****
				59 MACRO
				60 FCHECK &BITNO, &NOTSETMSG
				61 . * &BITNO : facility bit number to check
				62 . * &NOTSETMSG : 'facility name'
				63 LCLA &FBBYTE Facility bit in Byte
				64 LCLA &FBBIT Facility bit within Byte
				65
				66 LCLA &L(8)
				67 &L(1) SetA 128, 64, 32, 16, 8, 4, 2, 1 bit positions within byte
				68
				69 &FBBYTE SETA &BITNO/8
				70 &FBBIT SETA &L((&BITNO-(&FBBYTE*8))+1)
				71 . * MNOTE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'
				72
				73 B X&SYSNDX
				74 * Fcheck data area
				75 * skip messgae
				76 SKT&SYSNDX DC C' Skipping tests: '
				77 DC C&NOTSETMSG
				78 DC C' facility (bit &BITNO) is not installed.'
				79 SKL&SYSNDX EQU *-SKT&SYSNDX
				80 * facility bits
				81 DS FD gap
				82 FB&SYSNDX DS 4FD
				83 DS FD gap
				84 *
				85 X&SYSNDX EQU *
				86 LA R0, ((X&SYSNDX- FB&SYSNDX)/8)-1
				87 STFLE FB&SYSNDX get facility bits
				88
				89 XGR R0, R0
				90 IC R0, FB&SYSNDX+&FBBYTE get fbit byte
				91 N R0, =F' &FBBIT' is bit set?
				92 BNZ XC&SYSNDX
				93 *
				94 * facility bit not set, issue message and exit
				95 *
				96 LA R0, SKL&SYSNDX message length
				97 LA R1, SKT&SYSNDX message address
				98 BAL R2, MSG
				99
				100 B EOJ
				101 XC&SYSNDX EQU *
				102 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				124 *****
				125 * The actual "ZVE6TST" program itself...
				126 *****
				127 *
				128 * Architecture Mode: z/Arch
				129 * Register Usage:
				130 *
				131 * R0 (work)
				132 * R1-4 (work)
				133 * R5 Testing control table - current test base
				134 * R6- R7 (work)
				135 * R8 First base register
				136 * R9 Second base register
				137 * R10 Third base register
				138 * R11 E6TEST call return
				139 * R12 E6TESTS register
				140 * R13 (work)
				141 * R14 Subroutine call
				142 * R15 Secondary Subroutine call or work
				143 *
				144 *****
00000200		00000200		146 USING BEGIN, R8 FIRST Base Register
00000200		00001200		147 USING BEGIN+4096, R9 SECOND Base Register
00000200		00002200		148 USING BEGIN+8192, R10 THIRD Base Register
				149
00000200	0580			150 BEGIN BALR R8, 0 Initalize FIRST base register
00000202	0680			151 BCTR R8, 0 Initalize FIRST base register
00000204	0680			152 BCTR R8, 0 Initalize FIRST base register
				153
00000206	4190 8800		00000800	154 LA R9, 2048(, R8) Initalize SECOND base register
0000020A	4190 9800		00000800	155 LA R9, 2048(, R9) Initalize SECOND base register
				156
0000020E	41A0 9800		00000800	157 LA R10, 2048(, R9) Initalize THIRD base register
00000212	41A0 A800		00000800	158 LA R10, 2048(, R10) Initalize THIRD base register
				159
00000216	B600 82C4		000004C4	160 STCTL R0, R0, CTLR0 Store CRO to enable AFP
0000021A	9604 82C5		000004C5	161 OI CTLR0+1, X' 04' Turn on AFP bit
0000021E	9602 82C5		000004C5	162 OI CTLR0+1, X' 02' Turn on Vector bit
00000222	B700 82C4		000004C4	163 LCTL R0, R0, CTLR0 Reload updated CRO
				164
				165 *****
				166 * Is Vector packed-decimal facility installed (bit 134)
				167 *****
				168
00000226	47F0 80B0		000002B0	169 FCHECK 134, ' vector-packed- decimal '
				170+ B X0001
				171+* Fcheck data area
				172+* skip messgae
0000022A	40404040 40404040			173+SKT0001 DC C' Skipping tests: '
00000244	A58583A3 96996097			174+ DC C' vector-packed-decimal '
00000259	40868183 899389A3			175+ DC C' facility (bit 134) is not installed. '
		00000054 00000001		176+SKL0001 EQU *- SKT0001
				177+* facility bits
00000280	00000000 00000000			178+ DS FD gap
00000288	00000000 00000000			179+FB0001 DS 4FD

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				351 *****
				352 * Normal completion or Abnormal termination PSWs
				353 *****
00000498	00020001 80000000			355 E0JPSW DC OD' 0' , X' 0002000180000000' , AD(0)
000004A8	B2B2 8298		00000498	357 E0J LPSWE E0JPSW Normal completion
000004B0	00020001 80000000			359 FAILPSW DC OD' 0' , X' 0002000180000000' , AD(X' BAD')
000004C0	B2B2 82B0		000004B0	361 FAILTEST LPSWE FAILPSW Abnormal termination
				363 *****
				364 * Working Storage
				365 *****
000004C4	00000000			367 CTLR0 DS F CRO
000004C8	00000000			368 DS F
000004CC				370 LTORG , Literals pool
000004CC	00000002			371 =F' 2'
000004D0	00001990			372 =A(E6TESTS)
000004D4	00000003			373 =XL4' 3'
000004D8	00000001			374 =F' 1'
000004DC	0000			375 =H' 0'
000004DE	005F			376 =AL2(L' MSGMSG)
				377
				378 * some constants
				379
	00000400	00000001		380 K EQU 1024 One KB
	00001000	00000001		381 PAGE EQU (4*K) Size of one page
	00010000	00000001		382 K64 EQU (64*K) 64 KB
	00100000	00000001		383 MB EQU (K*K) 1 MB
				384
				385
	AABBCCDD	00000001		386 REG2PATT EQU X' AABBCCDD' Polluted Register pattern
	000000DD	00000001		387 REG2LOW EQU X' DD' (last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				473 *****
				474 * Macros to help build test tables
				475 *-----
				476 * VRR_H Macro to help build test tables
				477 *****
				478 MACRO
				479 VRR_H &INST, &MB, &CC
				480 . * &INST - instruction under test
				481 . * &CC - expected CC
				482 . *
				483 LCLA &XCC(4) &CC has mask values for FAILED condition codes
				484 &XCC(1) SETA 7 CC != 0
				485 &XCC(2) SETA 11 CC != 1
				486 &XCC(3) SETA 13 CC != 2
				487 &XCC(4) SETA 14 CC != 3
				488
				489 GBLA &TNUM
				490 &TNUM SETA &TNUM+1
				491
				492 DS 0FD
				493 USING *, R5 base for test data and test routine
				494
				495 T&TNUM DC A(X&TNUM) address of test routine
				496 DC H' &TNUM test number
				497 DC XL1' 00'
				498 DC HL1' &MB' mB
				499 DC HL1' &CC' cc
				500 DC HL1' &XCC(&CC+1)' cc failed mask
				501
				502 DC CL8' &INST' instruction name
				503
				504 DC A(16) result length
				505 REA&TNUM DC A(RE&TNUM) result address
				506 . *
				507 * INSTRUCTION UNDER TEST ROUTINE
				508 X&TNUM DS 0F
				509 VL V1, RE&TNUM get V1 source
				510 VL V2, RE&TNUM+16 get V2 source
				511
				512 &INST V1, V2, &MB test instruction
				513
				514 EPSW R2, R0 exptract psw
				515 ST R2, CCPSW to save CC
				516
				517 BR R11 return
				518
				519 RE&TNUM DC 0F
				520 DROP R5
				521
				522 MEND

524	*****		
525	*	PTTABLE Macro to generate table of pointers to individual tests	
526	*****		
527			
528		MACRO	
529		PTTABLE	
530		GBLA	&TNUM
531		LCLA	&CUR
532	&CUR	SETA	1
533	. *		
534	TTABLE	DS	OF
535	. LOOP	ANOP	
536	. *		
537		DC	A(T&CUR) address of test
538	. *		
539	&CUR	SETA	&CUR+1
540		AIF	(&CUR LE &TNUM) . LOOP
541	*		
542		DC	A(0) END OF TABLE
543		DC	A(0)
544	. *		
545		MEND	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				547 *****	
				548 * E6 VRR_H tests	
				549 *****	
00001148		00000000	000019FF	550 ZVE6TST CSECT ,	
				551 DS 0F	
				553 PRINT DATA	
				554 *	
				555 * E677 VCP - VECTOR COMPARE DECIMAL	
				556 * VRR_H instr, m3, cc	
				557 * followed by	
				558 * v1 - 16 byte source	
				559 * v2 - 16 byte source	
				560 *	
				561 * -----	
				562 * VCP - VECTOR COMPARE DECIMAL	
				563 * -----	
				564 * VCP simple	m3= 0 (P1=0, P2=0)
				565 *	m3= 4 (P1=0, P2=1)
				566 *	m3= 8 (P1=1, P2=0)
				567 *	m3=12 (P1=1, P2=1)
				568 * m3= 0 (P1=0, P2=0)	
00001148				569 VRR_H VCP, 0, 0	
00001148		00001148		570+ DS 0FD	
00001148	00001164			571+ USING *, R5	base for test data and test routine
0000114C	0001			572+T1 DC A(X1)	address of test routine
0000114E	00			573+ DC H' 1'	test number
0000114F	00			574+ DC XL1' 00'	
00001150	00			575+ DC HL1' 0'	m3
00001151	07			576+ DC HL1' 0'	cc
00001152	E5C3D740 40404040			577+ DC HL1' 7'	cc failed mask
0000115C	00000010			578+ DC CL8' VCP'	instruction name
00001160	00001180			579+ DC A(16)	result length
				580+REA1 DC A(RE1)	result address
				581+*	INSTRUCTION UNDER TEST ROUTINE
00001164				582+X1 DS 0F	
00001164	E710 5038 0006		00001180	583+ VL V1, RE1	get V1 source
0000116A	E720 5048 0006		00001190	584+ VL V2, RE1+16	get V2 source
00001170	E601 2000 0077			585+ VCP V1, V2, 0	test instruction
00001176	B98D 0020			586+ EPSW R2, R0	exptract psw
0000117A	5020 8E9C		0000109C	587+ ST R2, CCPSW	to save CC
0000117E	07FB			588+ BR R11	return
00001180				589+RE1 DC 0F	
00001180				590+ DROP R5	
00001180	00000000 00000000			591 DC XL16' 000000000000000000001234500000000D'	V1 source
00001188	00123450 0000000D				
00001190	00000000 00000000			592 DC XL16' 000000000000000000001234500000000D'	V2 source
00001198	00123450 0000000D				
				593	
000011A0				594 VRR_H VCP, 0, 0	
000011A0		000011A0		595+ DS 0FD	
000011A0	000011BC			596+ USING *, R5	base for test data and test routine
000011A4	0002			597+T2 DC A(X2)	address of test routine
000011A6	00			598+ DC H' 2'	test number
				599+ DC XL1' 00'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000011A7	00			600+	DC	HL1' 0'	m3
000011A8	00			601+	DC	HL1' 0'	cc
000011A9	07			602+	DC	HL1' 7'	cc failed mask
000011AA	E5C3D740 40404040			603+	DC	CL8' VCP'	instruction name
000011B4	00000010			604+	DC	A(16)	result length
000011B8	000011D8			605+REA2	DC	A(RE2)	result address
				606+*			INSTRUCTION UNDER TEST ROUTINE
000011BC				607+X2	DS	0F	
000011BC	E710 5038 0006		000011D8	608+	VL	V1, RE2	get V1 source
000011C2	E720 5048 0006		000011E8	609+	VL	V2, RE2+16	get V2 source
000011C8	E601 2000 0077			610+	VCP	V1, V2, 0	test instruction
000011CE	B98D 0020			611+	EPSW	R2, R0	exptract psw
000011D2	5020 8E9C		0000109C	612+	ST	R2, CCPSW	to save CC
000011D6	07FB			613+	BR	R11	return
000011D8				614+RE2	DC	0F	
000011D8				615+	DROP	R5	
000011D8	00000990 00000000			616	DC	XL16' 000009900000000000001234500000000C'	V1 source
000011E0	00123450 0000000C						
000011E8	00000990 00000000			617	DC	XL16' 000009900000000000001234500000000C'	V2 source
000011F0	00123450 0000000C						
				618			
				619	VRR_H	VCP, 0, 1	
000011F8				620+	DS	0FD	
000011F8		000011F8		621+	USING	*, R5	base for test data and test routine
000011F8	00001214			622+T3	DC	A(X3)	address of test routine
000011FC	0003			623+	DC	H' 3'	test number
000011FE	00			624+	DC	XL1' 00'	
000011FF	00			625+	DC	HL1' 0'	m3
00001200	01			626+	DC	HL1' 1'	cc
00001201	0B			627+	DC	HL1' 11'	cc failed mask
00001202	E5C3D740 40404040			628+	DC	CL8' VCP'	instruction name
0000120C	00000010			629+	DC	A(16)	result length
00001210	00001230			630+REA3	DC	A(RE3)	result address
				631+*			INSTRUCTION UNDER TEST ROUTINE
00001214				632+X3	DS	0F	
00001214	E710 9030 0006		00001230	633+	VL	V1, RE3	get V1 source
0000121A	E720 9040 0006		00001240	634+	VL	V2, RE3+16	get V2 source
00001220	E601 2000 0077			635+	VCP	V1, V2, 0	test instruction
00001226	B98D 0020			636+	EPSW	R2, R0	exptract psw
0000122A	5020 8E9C		0000109C	637+	ST	R2, CCPSW	to save CC
0000122E	07FB			638+	BR	R11	return
00001230				639+RE3	DC	0F	
00001230				640+	DROP	R5	
00001230	00000000 00000000			641	DC	XL16' 000000000000000000001234500000000D'	V1 source
00001238	00123450 0000000D						
00001240	00000000 00000000			642	DC	XL16' 000000000000000000001234500000000C'	V2 source
00001248	00123450 0000000C						
				643			
				644	VRR_H	VCP, 0, 1	
00001250				645+	DS	0FD	
00001250		00001250		646+	USING	*, R5	base for test data and test routine
00001250	0000126C			647+T4	DC	A(X4)	address of test routine
00001254	0004			648+	DC	H' 4'	test number
00001256	00			649+	DC	XL1' 00'	
00001257	00			650+	DC	HL1' 0'	m3
00001258	01			651+	DC	HL1' 1'	cc

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001259	0B			652+	DC	HL1' 11'	cc failed mask
0000125A	E5C3D740 40404040			653+	DC	CL8' VCP'	instruction name
00001264	00000010			654+	DC	A(16)	result length
00001268	00001288			655+REA4	DC	A(RE4)	result address
				656+*			INSTRUCTION UNDER TEST ROUTINE
0000126C				657+X4	DS	0F	
0000126C	E710 5038 0006		00001288	658+	VL	V1, RE4	get V1 source
00001272	E720 5048 0006		00001298	659+	VL	V2, RE4+16	get V2 source
00001278	E601 2000 0077			660+	VCP	V1, V2, 0	test instruction
0000127E	B98D 0020			661+	EPSW	R2, R0	exptract psw
00001282	5020 8E9C		0000109C	662+	ST	R2, CCPSW	to save CC
00001286	07FB			663+	BR	R11	return
00001288				664+RE4	DC	0F	
00001288				665+	DROP	R5	
00001288	00000990 00000000			666	DC	XL16' 000009900000000000000234500000000C'	V1 source
00001290	00023450 0000000C						
00001298	00000990 00000000			667	DC	XL16' 000009900000000000001234500000000C'	V2 source
000012A0	00123450 0000000C						
				668			
				669	VRR_H	VCP, 0, 2	
000012A8				670+	DS	0FD	
000012A8		000012A8		671+	USING	*, R5	base for test data and test routine
000012A8	000012C4			672+T5	DC	A(X5)	address of test routine
000012AC	0005			673+	DC	H' 5'	test number
000012AE	00			674+	DC	XL1' 00'	
000012AF	00			675+	DC	HL1' 0'	m3
000012B0	02			676+	DC	HL1' 2'	cc
000012B1	0D			677+	DC	HL1' 13'	cc failed mask
000012B2	E5C3D740 40404040			678+	DC	CL8' VCP'	instruction name
000012BC	00000010			679+	DC	A(16)	result length
000012C0	000012E0			680+REA5	DC	A(RE5)	result address
				681+*			INSTRUCTION UNDER TEST ROUTINE
000012C4				682+X5	DS	0F	
000012C4	E710 5038 0006		000012E0	683+	VL	V1, RE5	get V1 source
000012CA	E720 5048 0006		000012F0	684+	VL	V2, RE5+16	get V2 source
000012D0	E601 2000 0077			685+	VCP	V1, V2, 0	test instruction
000012D6	B98D 0020			686+	EPSW	R2, R0	exptract psw
000012DA	5020 8E9C		0000109C	687+	ST	R2, CCPSW	to save CC
000012DE	07FB			688+	BR	R11	return
000012E0				689+RE5	DC	0F	
000012E0				690+	DROP	R5	
000012E0	00000000 00000000			691	DC	XL16' 000000000000000000001234500000000C'	V1 source
000012E8	00123450 0000000C						
000012F0	00000000 00000000			692	DC	XL16' 000000000000000000001234500000000D'	V2 source
000012F8	00123450 0000000D						
				693			
				694	VRR_H	VCP, 0, 2	
00001300				695+	DS	0FD	
00001300		00001300		696+	USING	*, R5	base for test data and test routine
00001300	0000131C			697+T6	DC	A(X6)	address of test routine
00001304	0006			698+	DC	H' 6'	test number
00001306	00			699+	DC	XL1' 00'	
00001307	00			700+	DC	HL1' 0'	m3
00001308	02			701+	DC	HL1' 2'	cc
00001309	0D			702+	DC	HL1' 13'	cc failed mask
0000130A	E5C3D740 40404040			703+	DC	CL8' VCP'	instruction name

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001314	00000010			704+	DC	A(16)	result length
00001318	00001338			705+REA6	DC	A(RE6)	result address
				706+*			INSTRUCTION UNDER TEST ROUTINE
0000131C				707+X6	DS	0F	
0000131C	E710 5038 0006		00001338	708+	VL	V1, RE6	get V1 source
00001322	E720 5048 0006		00001348	709+	VL	V2, RE6+16	get V2 source
00001328	E601 2000 0077			710+	VCP	V1, V2, 0	test instruction
0000132E	B98D 0020			711+	EPSW	R2, R0	exptract psw
00001332	5020 8E9C		0000109C	712+	ST	R2, CCPSW	to save CC
00001336	07FB			713+	BR	R11	return
00001338				714+RE6	DC	0F	
00001338				715+	DROP	R5	
00001338	00000990 00000000			716	DC	XL16' 000009900000000000001234500000000C'	V1 source
00001340	00123450 0000000C						
00001348	00000990 00000000			717	DC	XL16' 000009900000000000000234500000000C'	V2 source
00001350	00023450 0000000C						
				718			
				719 * m3= 4	(P1=0, P2=1)		
				720	VRR_H VCP, 4, 1		
00001358				721+	DS	0FD	
00001358		00001358		722+	USING	*, R5	base for test data and test routine
00001358	00001374			723+T7	DC	A(X7)	address of test routine
0000135C	0007			724+	DC	H' 7'	test number
0000135E	00			725+	DC	XL1' 00'	
0000135F	04			726+	DC	HL1' 4'	m3
00001360	01			727+	DC	HL1' 1'	cc
00001361	0B			728+	DC	HL1' 11'	cc failed mask
00001362	E5C3D740 40404040			729+	DC	CL8' VCP'	instruction name
0000136C	00000010			730+	DC	A(16)	result length
00001370	00001390			731+REA7	DC	A(RE7)	result address
				732+*			INSTRUCTION UNDER TEST ROUTINE
00001374				733+X7	DS	0F	
00001374	E710 5038 0006		00001390	734+	VL	V1, RE7	get V1 source
0000137A	E720 5048 0006		000013A0	735+	VL	V2, RE7+16	get V2 source
00001380	E601 2040 0077			736+	VCP	V1, V2, 4	test instruction
00001386	B98D 0020			737+	EPSW	R2, R0	exptract psw
0000138A	5020 8E9C		0000109C	738+	ST	R2, CCPSW	to save CC
0000138E	07FB			739+	BR	R11	return
00001390				740+RE7	DC	0F	
00001390				741+	DROP	R5	
00001390	00000000 00000000			742	DC	XL16' 000000000000000000001234500000000D'	V1 source
00001398	00123450 0000000D						
000013A0	00000000 00000000			743	DC	XL16' 000000000000000000001234500000000D'	V2 source
000013A8	00123450 0000000D						
				744			
000013B0				745	VRR_H VCP, 4, 0		
000013B0		000013B0		746+	DS	0FD	
000013B0	000013CC			747+	USING	*, R5	base for test data and test routine
000013B4	0008			748+T8	DC	A(X8)	address of test routine
000013B6	00			749+	DC	H' 8'	test number
000013B6	00			750+	DC	XL1' 00'	
000013B7	04			751+	DC	HL1' 4'	m3
000013B8	00			752+	DC	HL1' 0'	cc
000013B9	07			753+	DC	HL1' 7'	cc failed mask
000013BA	E5C3D740 40404040			754+	DC	CL8' VCP'	instruction name
000013C4	00000010			755+	DC	A(16)	result length

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000013C8	000013E8			756+REA8	DC	A(RE8)	result address
				757+*			INSTRUCTION UNDER TEST ROUTINE
000013CC				758+X8	DS	0F	
000013CC	E710 5038 0006		000013E8	759+	VL	V1, RE8	get V1 source
000013D2	E720 5048 0006		000013F8	760+	VL	V2, RE8+16	get V2 source
000013D8	E601 2040 0077			761+	VCP	V1, V2, 4	test instruction
000013DE	B98D 0020			762+	EPSW	R2, R0	exptract psw
000013E2	5020 8E9C		0000109C	763+	ST	R2, CCPSW	to save CC
000013E6	07FB			764+	BR	R11	return
000013E8				765+RE8	DC	0F	
000013E8				766+	DROP	R5	
000013E8	00000990 00000000			767	DC	XL16' 000009900000000000001234500000000C'	V1 source
000013F0	00123450 0000000C						
000013F8	00000990 00000000			768	DC	XL16' 000009900000000000001234500000000C'	V2 source
00001400	00123450 0000000C						
				769			
				770	VRR_H	VCP, 4, 1	
00001408				771+	DS	0FD	
00001408		00001408		772+	USING	*, R5	base for test data and test routine
00001408	00001424			773+T9	DC	A(X9)	address of test routine
0000140C	0009			774+	DC	H' 9'	test number
0000140E	00			775+	DC	XL1' 00'	
0000140F	04			776+	DC	HL1' 4'	m3
00001410	01			777+	DC	HL1' 1'	cc
00001411	0B			778+	DC	HL1' 11'	cc failed mask
00001412	E5C3D740 40404040			779+	DC	CL8' VCP'	instruction name
0000141C	00000010			780+	DC	A(16)	result length
00001420	00001440			781+REA9	DC	A(RE9)	result address
				782+*			INSTRUCTION UNDER TEST ROUTINE
00001424				783+X9	DS	0F	
00001424	E710 5038 0006		00001440	784+	VL	V1, RE9	get V1 source
0000142A	E720 5048 0006		00001450	785+	VL	V2, RE9+16	get V2 source
00001430	E601 2040 0077			786+	VCP	V1, V2, 4	test instruction
00001436	B98D 0020			787+	EPSW	R2, R0	exptract psw
0000143A	5020 8E9C		0000109C	788+	ST	R2, CCPSW	to save CC
0000143E	07FB			789+	BR	R11	return
00001440				790+RE9	DC	0F	
00001440				791+	DROP	R5	
00001440	00000000 00000000			792	DC	XL16' 000000000000000000001234500000000D'	V1 source
00001448	00123450 0000000D						
00001450	00000000 00000000			793	DC	XL16' 000000000000000000001234500000000C'	V2 source
00001458	00123450 0000000C						
				794			
				795	VRR_H	VCP, 4, 1	
00001460				796+	DS	0FD	
00001460		00001460		797+	USING	*, R5	base for test data and test routine
00001460	0000147C			798+T10	DC	A(X10)	address of test routine
00001464	000A			799+	DC	H' 10'	test number
00001466	00			800+	DC	XL1' 00'	
00001467	04			801+	DC	HL1' 4'	m3
00001468	01			802+	DC	HL1' 1'	cc
00001469	0B			803+	DC	HL1' 11'	cc failed mask
0000146A	E5C3D740 40404040			804+	DC	CL8' VCP'	instruction name
00001474	00000010			805+	DC	A(16)	result length
00001478	00001498			806+REA10	DC	A(RE10)	result address
				807+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000147C				808+X10	DS	0F	
0000147C	E710 5038 0006		00001498	809+	VL	V1, RE10	get V1 source
00001482	E720 5048 0006		000014A8	810+	VL	V2, RE10+16	get V2 source
00001488	E601 2040 0077			811+	VCP	V1, V2, 4	test instruction
0000148E	B98D 0020			812+	EPSW	R2, R0	exptract psw
00001492	5020 8E9C		0000109C	813+	ST	R2, CCPSW	to save CC
00001496	07FB			814+	BR	R11	return
00001498				815+RE10	DC	0F	
00001498				816+	DROP	R5	
00001498	00000990 00000000			817	DC	XL16' 000009900000000000000234500000000C'	V1 source
000014A0	00023450 0000000C						
000014A8	00000990 00000000			818	DC	XL16' 000009900000000000001234500000000C'	V2 source
000014B0	00123450 0000000C						
				819			
				820	VRR_H	VCP, 4, 0	
000014B8				821+	DS	0FD	
000014B8		000014B8		822+	USING	*, R5	base for test data and test routine
000014B8	000014D4			823+T11	DC	A(X11)	address of test routine
000014BC	000B			824+	DC	H' 11'	test number
000014BE	00			825+	DC	XL1' 00'	
000014BF	04			826+	DC	HL1' 4'	m3
000014C0	00			827+	DC	HL1' 0'	cc
000014C1	07			828+	DC	HL1' 7'	cc failed mask
000014C2	E5C3D740 40404040			829+	DC	CL8' VCP'	instruction name
000014CC	00000010			830+	DC	A(16)	result length
000014D0	000014F0			831+REA11	DC	A(RE11)	result address
				832+*			INSTRUCTION UNDER TEST ROUTINE
000014D4				833+X11	DS	0F	
000014D4	E710 5038 0006		000014F0	834+	VL	V1, RE11	get V1 source
000014DA	E720 5048 0006		00001500	835+	VL	V2, RE11+16	get V2 source
000014E0	E601 2040 0077			836+	VCP	V1, V2, 4	test instruction
000014E6	B98D 0020			837+	EPSW	R2, R0	exptract psw
000014EA	5020 8E9C		0000109C	838+	ST	R2, CCPSW	to save CC
000014EE	07FB			839+	BR	R11	return
000014F0				840+RE11	DC	0F	
000014F0				841+	DROP	R5	
000014F0	00000000 00000000			842	DC	XL16' 000000000000000000001234500000000C'	V1 source
000014F8	00123450 0000000C						
00001500	00000000 00000000			843	DC	XL16' 000000000000000000001234500000000D'	V2 source
00001508	00123450 0000000D						
				844			
				845	VRR_H	VCP, 4, 2	
00001510				846+	DS	0FD	
00001510		00001510		847+	USING	*, R5	base for test data and test routine
00001510	0000152C			848+T12	DC	A(X12)	address of test routine
00001514	000C			849+	DC	H' 12'	test number
00001516	00			850+	DC	XL1' 00'	
00001517	04			851+	DC	HL1' 4'	m3
00001518	02			852+	DC	HL1' 2'	cc
00001519	0D			853+	DC	HL1' 13'	cc failed mask
0000151A	E5C3D740 40404040			854+	DC	CL8' VCP'	instruction name
00001524	00000010			855+	DC	A(16)	result length
00001528	00001548			856+REA12	DC	A(RE12)	result address
				857+*			INSTRUCTION UNDER TEST ROUTINE
0000152C				858+X12	DS	0F	
0000152C	E710 5038 0006		00001548	859+	VL	V1, RE12	get V1 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001532	E720 5048 0006		00001558	860+	VL	V2, RE12+16	get V2 source
00001538	E601 2040 0077			861+	VCP	V1, V2, 4	test instruction
0000153E	B98D 0020			862+	EPSW	R2, R0	exptrect psw
00001542	5020 8E9C		0000109C	863+	ST	R2, CCPSW	to save CC
00001546	07FB			864+	BR	R11	return
00001548				865+RE12	DC	0F	
00001548				866+	DROP	R5	
00001548	00000990 00000000			867	DC	XL16' 000009900000000000001234500000000C'	V1 source
00001550	00123450 0000000C						
00001558	00000990 00000000			868	DC	XL16' 000009900000000000000234500000000C'	V2 source
00001560	00023450 0000000C						
				869			
				870 * m3= 8	(P1=1, P2=0)		
				871	VRR_H	VCP, 8, 2	
00001568				872+	DS	0FD	
00001568		00001568		873+	USING	*, R5	base for test data and test routine
00001568	00001584			874+T13	DC	A(X13)	address of test routine
0000156C	000D			875+	DC	H' 13'	test number
0000156E	00			876+	DC	XL1' 00'	
0000156F	08			877+	DC	HL1' 8'	m3
00001570	02			878+	DC	HL1' 2'	cc
00001571	0D			879+	DC	HL1' 13'	cc failed mask
00001572	E5C3D740 40404040			880+	DC	CL8' VCP'	instruction name
0000157C	00000010			881+	DC	A(16)	result length
00001580	000015A0			882+REA13	DC	A(RE13)	result address
				883+*			INSTRUCTION UNDER TEST ROUTINE
00001584				884+X13	DS	0F	
00001584	E710 5038 0006		000015A0	885+	VL	V1, RE13	get V1 source
0000158A	E720 5048 0006		000015B0	886+	VL	V2, RE13+16	get V2 source
00001590	E601 2080 0077			887+	VCP	V1, V2, 8	test instruction
00001596	B98D 0020			888+	EPSW	R2, R0	exptrect psw
0000159A	5020 8E9C		0000109C	889+	ST	R2, CCPSW	to save CC
0000159E	07FB			890+	BR	R11	return
000015A0				891+RE13	DC	0F	
000015A0				892+	DROP	R5	
000015A0	00000000 00000000			893	DC	XL16' 000000000000000000001234500000000D'	V1 source
000015A8	00123450 0000000D						
000015B0	00000000 00000000			894	DC	XL16' 000000000000000000001234500000000D'	V2 source
000015B8	00123450 0000000D						
				895			
				896	VRR_H	VCP, 8, 0	
000015C0				897+	DS	0FD	
000015C0		000015C0		898+	USING	*, R5	base for test data and test routine
000015C0	000015DC			899+T14	DC	A(X14)	address of test routine
000015C4	000E			900+	DC	H' 14'	test number
000015C6	00			901+	DC	XL1' 00'	
000015C7	08			902+	DC	HL1' 8'	m3
000015C8	00			903+	DC	HL1' 0'	cc
000015C9	07			904+	DC	HL1' 7'	cc failed mask
000015CA	E5C3D740 40404040			905+	DC	CL8' VCP'	instruction name
000015D4	00000010			906+	DC	A(16)	result length
000015D8	000015F8			907+REA14	DC	A(RE14)	result address
				908+*			INSTRUCTION UNDER TEST ROUTINE
000015DC				909+X14	DS	0F	
000015DC	E710 5038 0006		000015F8	910+	VL	V1, RE14	get V1 source
000015E2	E720 5048 0006		00001608	911+	VL	V2, RE14+16	get V2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000015E8	E601 2080 0077			912+	VCP	V1, V2, 8	test instruction
000015EE	B98D 0020			913+	EPSW	R2, R0	exptract psw
000015F2	5020 8E9C		0000109C	914+	ST	R2, CCPSW	to save CC
000015F6	07FB			915+	BR	R11	return
000015F8				916+RE14	DC	0F	
000015F8				917+	DROP	R5	
000015F8	00000990 00000000			918	DC	XL16' 00000990000000000001234500000000C'	V1 source
00001600	00123450 0000000C						
00001608	00000990 00000000			919	DC	XL16' 00000990000000000001234500000000C'	V2 source
00001610	00123450 0000000C						
				920			
00001618				921	VRR_H	VCP, 8, 0	
00001618		00001618		922+	DS	0FD	
00001618	00001634			923+	USING	*, R5	base for test data and test routine
0000161C	000F			924+T15	DC	A(X15)	address of test routine
0000161E	00			925+	DC	H' 15'	test number
0000161F	08			926+	DC	XL1' 00'	
00001620	00			927+	DC	HL1' 8'	m3
00001621	07			928+	DC	HL1' 0'	cc
00001622	E5C3D740 40404040			929+	DC	HL1' 7'	cc failed mask
0000162C	00000010			930+	DC	CL8' VCP'	instruction name
00001630	00001650			931+	DC	A(16)	result length
				932+REA15	DC	A(RE15)	result address
				933+*			INSTRUCTION UNDER TEST ROUTINE
00001634				934+X15	DS	0F	
00001634	E710 5038 0006		00001650	935+	VL	V1, RE15	get V1 source
0000163A	E720 5048 0006		00001660	936+	VL	V2, RE15+16	get V2 source
00001640	E601 2080 0077			937+	VCP	V1, V2, 8	test instruction
00001646	B98D 0020			938+	EPSW	R2, R0	exptract psw
0000164A	5020 8E9C		0000109C	939+	ST	R2, CCPSW	to save CC
0000164E	07FB			940+	BR	R11	return
00001650				941+RE15	DC	0F	
00001650				942+	DROP	R5	
00001650	00000000 00000000			943	DC	XL16' 00000000000000000001234500000000D'	V1 source
00001658	00123450 0000000D						
00001660	00000000 00000000			944	DC	XL16' 00000000000000000001234500000000C'	V2 source
00001668	00123450 0000000C						
				945			
00001670				946	VRR_H	VCP, 8, 1	
00001670		00001670		947+	DS	0FD	
00001670	0000168C			948+	USING	*, R5	base for test data and test routine
00001674	0010			949+T16	DC	A(X16)	address of test routine
00001676	00			950+	DC	H' 16'	test number
00001676	00			951+	DC	XL1' 00'	
00001677	08			952+	DC	HL1' 8'	m3
00001678	01			953+	DC	HL1' 1'	cc
00001679	0B			954+	DC	HL1' 11'	cc failed mask
0000167A	E5C3D740 40404040			955+	DC	CL8' VCP'	instruction name
00001684	00000010			956+	DC	A(16)	result length
00001688	000016A8			957+REA16	DC	A(RE16)	result address
				958+*			INSTRUCTION UNDER TEST ROUTINE
0000168C				959+X16	DS	0F	
0000168C	E710 5038 0006		000016A8	960+	VL	V1, RE16	get V1 source
00001692	E720 5048 0006		000016B8	961+	VL	V2, RE16+16	get V2 source
00001698	E601 2080 0077			962+	VCP	V1, V2, 8	test instruction
0000169E	B98D 0020			963+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016A2	5020 8E9C		0000109C	964+	ST	R2, CCPSW	to save CC
000016A6	07FB			965+	BR	R11	return
000016A8				966+RE16	DC	0F	
000016A8				967+	DROP	R5	
000016A8	00000990 00000000			968	DC	XL16' 000009900000000000000234500000000C'	V1 source
000016B0	00023450 0000000C						
000016B8	00000990 00000000			969	DC	XL16' 000009900000000000001234500000000C'	V2 source
000016C0	00123450 0000000C						
				970			
				971	VRR_H	VCP, 8, 2	
000016C8				972+	DS	0FD	
000016C8		000016C8		973+	USING	*, R5	base for test data and test routine
000016C8	000016E4			974+T17	DC	A(X17)	address of test routine
000016CC	0011			975+	DC	H' 17'	test number
000016CE	00			976+	DC	XL1' 00'	
000016CF	08			977+	DC	HL1' 8'	m3
000016D0	02			978+	DC	HL1' 2'	cc
000016D1	0D			979+	DC	HL1' 13'	cc failed mask
000016D2	E5C3D740 40404040			980+	DC	CL8' VCP'	instruction name
000016DC	00000010			981+	DC	A(16)	result length
000016E0	00001700			982+REA17	DC	A(RE17)	result address
				983+*			INSTRUCTION UNDER TEST ROUTINE
000016E4				984+X17	DS	0F	
000016E4	E710 5038 0006		00001700	985+	VL	V1, RE17	get V1 source
000016EA	E720 5048 0006		00001710	986+	VL	V2, RE17+16	get V2 source
000016F0	E601 2080 0077			987+	VCP	V1, V2, 8	test instruction
000016F6	B98D 0020			988+	EPSW	R2, R0	exptract psw
000016FA	5020 8E9C		0000109C	989+	ST	R2, CCPSW	to save CC
000016FE	07FB			990+	BR	R11	return
00001700				991+RE17	DC	0F	
00001700				992+	DROP	R5	
00001700	00000000 00000000			993	DC	XL16' 000000000000000000001234500000000C'	V1 source
00001708	00123450 0000000C						
00001710	00000000 00000000			994	DC	XL16' 000000000000000000001234500000000D'	V2 source
00001718	00123450 0000000D						
				995			
				996	VRR_H	VCP, 8, 2	
00001720				997+	DS	0FD	
00001720		00001720		998+	USING	*, R5	base for test data and test routine
00001720	0000173C			999+T18	DC	A(X18)	address of test routine
00001724	0012			1000+	DC	H' 18'	test number
00001726	00			1001+	DC	XL1' 00'	
00001727	08			1002+	DC	HL1' 8'	m3
00001728	02			1003+	DC	HL1' 2'	cc
00001729	0D			1004+	DC	HL1' 13'	cc failed mask
0000172A	E5C3D740 40404040			1005+	DC	CL8' VCP'	instruction name
00001734	00000010			1006+	DC	A(16)	result length
00001738	00001758			1007+REA18	DC	A(RE18)	result address
				1008+*			INSTRUCTION UNDER TEST ROUTINE
0000173C				1009+X18	DS	0F	
0000173C	E710 5038 0006		00001758	1010+	VL	V1, RE18	get V1 source
00001742	E720 5048 0006		00001768	1011+	VL	V2, RE18+16	get V2 source
00001748	E601 2080 0077			1012+	VCP	V1, V2, 8	test instruction
0000174E	B98D 0020			1013+	EPSW	R2, R0	exptract psw
00001752	5020 8E9C		0000109C	1014+	ST	R2, CCPSW	to save CC
00001756	07FB			1015+	BR	R11	return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001758				1016+RE18	DC	0F	
00001758				1017+	DROP	R5	
00001758	00000990 00000000			1018	DC	XL16' 000009900000000000001234500000000C'	V1 source
00001760	00123450 0000000C						
00001768	00000990 00000000			1019	DC	XL16' 00000990000000000000234500000000C'	V2 source
00001770	00023450 0000000C						
				1020			
				1021 * mB=12	(P1=1, P2=1)		
				1022	VRR_H	VCP, 12, 0	
00001778		00001778		1023+	DS	0FD	
00001778				1024+	USING	*, R5	base for test data and test routine
00001778	00001794			1025+T19	DC	A(X19)	address of test routine
0000177C	0013			1026+	DC	H' 19'	test number
0000177E	00			1027+	DC	XL1' 00'	
0000177F	0C			1028+	DC	HL1' 12'	mB
00001780	00			1029+	DC	HL1' 0'	cc
00001781	07			1030+	DC	HL1' 7'	cc failed mask
00001782	E5C3D740 40404040			1031+	DC	CL8' VCP'	instruction name
0000178C	00000010			1032+	DC	A(16)	result length
00001790	000017B0			1033+REA19	DC	A(RE19)	result address
				1034+*			INSTRUCTION UNDER TEST ROUTINE
00001794				1035+X19	DS	0F	
00001794	E710 5038 0006		000017B0	1036+	VL	V1, RE19	get V1 source
0000179A	E720 5048 0006		000017C0	1037+	VL	V2, RE19+16	get V2 source
000017A0	E601 20C0 0077			1038+	VCP	V1, V2, 12	test instruction
000017A6	B98D 0020			1039+	EPSW	R2, R0	extract psw
000017AA	5020 8E9C		0000109C	1040+	ST	R2, CCPSW	to save CC
000017AE	07FB			1041+	BR	R11	return
000017B0				1042+RE19	DC	0F	
000017B0				1043+	DROP	R5	
000017B0	00000000 00000000			1044	DC	XL16' 000000000000000000001234500000000D'	V1 source
000017B8	00123450 0000000D						
000017C0	00000000 00000000			1045	DC	XL16' 000000000000000000001234500000000D'	V2 source
000017C8	00123450 0000000D						
				1046			
				1047	VRR_H	VCP, 12, 0	
000017D0		000017D0		1048+	DS	0FD	
000017D0				1049+	USING	*, R5	base for test data and test routine
000017D0	000017EC			1050+T20	DC	A(X20)	address of test routine
000017D4	0014			1051+	DC	H' 20'	test number
000017D6	00			1052+	DC	XL1' 00'	
000017D7	0C			1053+	DC	HL1' 12'	mB
000017D8	00			1054+	DC	HL1' 0'	cc
000017D9	07			1055+	DC	HL1' 7'	cc failed mask
000017DA	E5C3D740 40404040			1056+	DC	CL8' VCP'	instruction name
000017E4	00000010			1057+	DC	A(16)	result length
000017E8	00001808			1058+REA20	DC	A(RE20)	result address
				1059+*			INSTRUCTION UNDER TEST ROUTINE
000017EC				1060+X20	DS	0F	
000017EC	E710 5038 0006		00001808	1061+	VL	V1, RE20	get V1 source
000017F2	E720 5048 0006		00001818	1062+	VL	V2, RE20+16	get V2 source
000017F8	E601 20C0 0077			1063+	VCP	V1, V2, 12	test instruction
000017FE	B98D 0020			1064+	EPSW	R2, R0	extract psw
00001802	5020 8E9C		0000109C	1065+	ST	R2, CCPSW	to save CC
00001806	07FB			1066+	BR	R11	return
00001808				1067+RE20	DC	0F	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001808				1068+	DROP R5		
00001808	00000990 00000000			1069	DC	XL16' 000009900000000000001234500000000C'	V1 source
00001810	00123450 0000000C						
00001818	00000990 00000000			1070	DC	XL16' 000009900000000000001234500000000C'	V2 source
00001820	00123450 0000000C						
				1071			
				1072	VRR_H VCP, 12, 0		
00001828				1073+	DS OFD		
00001828		00001828		1074+	USING *, R5	base for test data and test routine	
00001828	00001844			1075+T21	DC A(X21)	address of test routine	
0000182C	0015			1076+	DC H' 21'	test number	
0000182E	00			1077+	DC XL1' 00'		
0000182F	0C			1078+	DC HL1' 12'	m3	
00001830	00			1079+	DC HL1' 0'	cc	
00001831	07			1080+	DC HL1' 7'	cc failed mask	
00001832	E5C3D740 40404040			1081+	DC CL8' VCP'	instruction name	
0000183C	00000010			1082+	DC A(16)	result length	
00001840	00001860			1083+REA21	DC A(RE21)	result address	
				1084+*		INSTRUCTION UNDER TEST ROUTINE	
00001844				1085+X21	DS OF		
00001844	E710 5038 0006		00001860	1086+	VL V1, RE21	get V1 source	
0000184A	E720 5048 0006		00001870	1087+	VL V2, RE21+16	get V2 source	
00001850	E601 20C0 0077			1088+	VCP V1, V2, 12	test instruction	
00001856	B98D 0020			1089+	EPSW R2, R0	exptract psw	
0000185A	5020 8E9C		0000109C	1090+	ST R2, CCPSW	to save CC	
0000185E	07FB			1091+	BR R11	return	
00001860				1092+RE21	DC OF		
00001860				1093+	DROP R5		
00001860	00000000 00000000			1094	DC	XL16' 000000000000000000001234500000000D'	V1 source
00001868	00123450 0000000D						
00001870	00000000 00000000			1095	DC	XL16' 000000000000000000001234500000000C'	V2 source
00001878	00123450 0000000C						
				1096			
				1097	VRR_H VCP, 12, 1		
00001880				1098+	DS OFD		
00001880		00001880		1099+	USING *, R5	base for test data and test routine	
00001880	0000189C			1100+T22	DC A(X22)	address of test routine	
00001884	0016			1101+	DC H' 22'	test number	
00001886	00			1102+	DC XL1' 00'		
00001887	0C			1103+	DC HL1' 12'	m3	
00001888	01			1104+	DC HL1' 1'	cc	
00001889	0B			1105+	DC HL1' 11'	cc failed mask	
0000188A	E5C3D740 40404040			1106+	DC CL8' VCP'	instruction name	
00001894	00000010			1107+	DC A(16)	result length	
00001898	000018B8			1108+REA22	DC A(RE22)	result address	
				1109+*		INSTRUCTION UNDER TEST ROUTINE	
0000189C				1110+X22	DS OF		
0000189C	E710 5038 0006		000018B8	1111+	VL V1, RE22	get V1 source	
000018A2	E720 5048 0006		000018C8	1112+	VL V2, RE22+16	get V2 source	
000018A8	E601 20C0 0077			1113+	VCP V1, V2, 12	test instruction	
000018AE	B98D 0020			1114+	EPSW R2, R0	exptract psw	
000018B2	5020 8E9C		0000109C	1115+	ST R2, CCPSW	to save CC	
000018B6	07FB			1116+	BR R11	return	
000018B8				1117+RE22	DC OF		
000018B8				1118+	DROP R5		
000018B8	00000990 00000000			1119	DC	XL16' 00000990000000000000234500000000C'	V1 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000018C0	00023450 0000000C						
000018C8	00000990 00000000			1120	DC	XL16' 000009900000000000001234500000000C'	V2 source
000018D0	00123450 0000000C						
				1121			
				1122	VRR_H	VCP, 12, 0	
000018D8				1123+	DS	OFD	
000018D8		000018D8		1124+	USING	*, R5	base for test data and test routine
000018D8	000018F4			1125+T23	DC	A(X23)	address of test routine
000018DC	0017			1126+	DC	H' 23'	test number
000018DE	00			1127+	DC	XL1' 00'	
000018DF	0C			1128+	DC	HL1' 12'	m3
000018E0	00			1129+	DC	HL1' 0'	cc
000018E1	07			1130+	DC	HL1' 7'	cc failed mask
000018E2	E5C3D740 40404040			1131+	DC	CL8' VCP'	instruction name
000018EC	00000010			1132+	DC	A(16)	result length
000018F0	00001910			1133+REA23	DC	A(RE23)	result address
				1134+*			INSTRUCTION UNDER TEST ROUTINE
000018F4				1135+X23	DS	OF	
000018F4	E710 5038 0006		00001910	1136+	VL	V1, RE23	get V1 source
000018FA	E720 5048 0006		00001920	1137+	VL	V2, RE23+16	get V2 source
00001900	E601 20C0 0077			1138+	VCP	V1, V2, 12	test instruction
00001906	B98D 0020			1139+	EPSW	R2, R0	exptract psw
0000190A	5020 8E9C		0000109C	1140+	ST	R2, CCPSW	to save CC
0000190E	07FB			1141+	BR	R11	return
00001910				1142+RE23	DC	OF	
00001910				1143+	DROP	R5	
00001910	00000000 00000000			1144	DC	XL16' 000000000000000000001234500000000C'	V1 source
00001918	00123450 0000000C						
00001920	00000000 00000000			1145	DC	XL16' 000000000000000000001234500000000D'	V2 source
00001928	00123450 0000000D						
				1146			
				1147	VRR_H	VCP, 12, 2	
00001930				1148+	DS	OFD	
00001930		00001930		1149+	USING	*, R5	base for test data and test routine
00001930	0000194C			1150+T24	DC	A(X24)	address of test routine
00001934	0018			1151+	DC	H' 24'	test number
00001936	00			1152+	DC	XL1' 00'	
00001937	0C			1153+	DC	HL1' 12'	m3
00001938	02			1154+	DC	HL1' 2'	cc
00001939	0D			1155+	DC	HL1' 13'	cc failed mask
0000193A	E5C3D740 40404040			1156+	DC	CL8' VCP'	instruction name
00001944	00000010			1157+	DC	A(16)	result length
00001948	00001968			1158+REA24	DC	A(RE24)	result address
				1159+*			INSTRUCTION UNDER TEST ROUTINE
0000194C				1160+X24	DS	OF	
0000194C	E710 5038 0006		00001968	1161+	VL	V1, RE24	get V1 source
00001952	E720 5048 0006		00001978	1162+	VL	V2, RE24+16	get V2 source
00001958	E601 20C0 0077			1163+	VCP	V1, V2, 12	test instruction
0000195E	B98D 0020			1164+	EPSW	R2, R0	exptract psw
00001962	5020 8E9C		0000109C	1165+	ST	R2, CCPSW	to save CC
00001966	07FB			1166+	BR	R11	return
00001968				1167+RE24	DC	OF	
00001968				1168+	DROP	R5	
00001968	00000990 00000000			1169	DC	XL16' 000009900000000000001234500000000C'	V1 source
00001970	00123450 0000000C						
00001978	00000990 00000000			1170	DC	XL16' 00000990000000000000234500000000C'	V2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
00001980	00023450 0000000C			1171
00001988	00000000			1172
0000198C	00000000			1173
				1174 *
				1175 * table of pointers to individual load test
				1176 *
00001990				1177 E6TESTS DS OF
				1178 PTTABLE
00001990				1179+TTABLE DS OF
00001990	00001148			1180+ DC A(T1) address of test
00001994	000011A0			1181+ DC A(T2) address of test
00001998	000011F8			1182+ DC A(T3) address of test
0000199C	00001250			1183+ DC A(T4) address of test
000019A0	000012A8			1184+ DC A(T5) address of test
000019A4	00001300			1185+ DC A(T6) address of test
000019A8	00001358			1186+ DC A(T7) address of test
000019AC	000013B0			1187+ DC A(T8) address of test
000019B0	00001408			1188+ DC A(T9) address of test
000019B4	00001460			1189+ DC A(T10) address of test
000019B8	000014B8			1190+ DC A(T11) address of test
000019BC	00001510			1191+ DC A(T12) address of test
000019C0	00001568			1192+ DC A(T13) address of test
000019C4	000015C0			1193+ DC A(T14) address of test
000019C8	00001618			1194+ DC A(T15) address of test
000019CC	00001670			1195+ DC A(T16) address of test
000019D0	000016C8			1196+ DC A(T17) address of test
000019D4	00001720			1197+ DC A(T18) address of test
000019D8	00001778			1198+ DC A(T19) address of test
000019DC	000017D0			1199+ DC A(T20) address of test
000019E0	00001828			1200+ DC A(T21) address of test
000019E4	00001880			1201+ DC A(T22) address of test
000019E8	000018D8			1202+ DC A(T23) address of test
000019EC	00001930			1203+ DC A(T24) address of test
				1204+*
000019F0	00000000			1205+ DC A(0) END OF TABLE
000019F4	00000000			1206+ DC A(0)
				1207
000019F8	00000000			1208 DC F' 0' END OF TABLE
000019FC	00000000			1209 DC F' 0'

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1211	*****
				1212	* Register equates
				1213	*****
		00000000	00000001	1215 R0	EQU 0
		00000001	00000001	1216 R1	EQU 1
		00000002	00000001	1217 R2	EQU 2
		00000003	00000001	1218 R3	EQU 3
		00000004	00000001	1219 R4	EQU 4
		00000005	00000001	1220 R5	EQU 5
		00000006	00000001	1221 R6	EQU 6
		00000007	00000001	1222 R7	EQU 7
		00000008	00000001	1223 R8	EQU 8
		00000009	00000001	1224 R9	EQU 9
		0000000A	00000001	1225 R10	EQU 10
		0000000B	00000001	1226 R11	EQU 11
		0000000C	00000001	1227 R12	EQU 12
		0000000D	00000001	1228 R13	EQU 13
		0000000E	00000001	1229 R14	EQU 14
		0000000F	00000001	1230 R15	EQU 15
				1232	*****
				1233	* Register equates
				1234	*****
		00000000	00000001	1236 V0	EQU 0
		00000001	00000001	1237 V1	EQU 1
		00000002	00000001	1238 V2	EQU 2
		00000003	00000001	1239 V3	EQU 3
		00000004	00000001	1240 V4	EQU 4
		00000005	00000001	1241 V5	EQU 5
		00000006	00000001	1242 V6	EQU 6
		00000007	00000001	1243 V7	EQU 7
		00000008	00000001	1244 V8	EQU 8
		00000009	00000001	1245 V9	EQU 9
		0000000A	00000001	1246 V10	EQU 10
		0000000B	00000001	1247 V11	EQU 11
		0000000C	00000001	1248 V12	EQU 12
		0000000D	00000001	1249 V13	EQU 13
		0000000E	00000001	1250 V14	EQU 14
		0000000F	00000001	1251 V15	EQU 15
		00000010	00000001	1252 V16	EQU 16
		00000011	00000001	1253 V17	EQU 17
		00000012	00000001	1254 V18	EQU 18
		00000013	00000001	1255 V19	EQU 19
		00000014	00000001	1256 V20	EQU 20
		00000015	00000001	1257 V21	EQU 21

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image	IMAGE	6656	0000- 19FF	0000- 19FF
Regi on		6656	0000- 19FF	0000- 19FF
CSECT	ZVE6TST	6656	0000- 19FF	0000- 19FF

STMT	FILE NAME
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1	/home/tn529/sharedvfp/tests/zvector-e6-15-comparedecimal.asm
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**** NO ERRORS FOUND ****